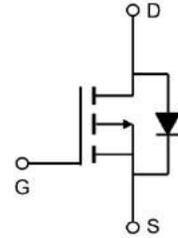


## 200V P-Channel Enhancement Mode MOSFET

### Description

The 13P20 is silicon P-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.



### General Features

$V_{DS} = -200V, I_D = -13A$

$R_{DS(ON)} < 0.42\Omega @ V_{GS} = 10V$

### Application

Power amplifier

motor drive



### Absolute Maximum Ratings ( $T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-200	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D T_C = 25^\circ C$	Continuous Drain Current	-13	A
$I_D T_C = 100^\circ C$	Continuous Drain Current	-7.2	A
IDM	Pulsed Drain Current <sup>a</sup>	-52	A
EAS	Single Pulse Avalanche Energy <sup>b</sup>	750	mJ
IAR	Repetitive Avalanche Current <sup>a</sup>	-11	A
EAR	Repetitive Avalanche Energy <sup>a</sup>	13	mJ
$P_D T_C = 25^\circ C$	Maximum Power Dissipation	125	W
dV/dt	Peak Diode Recovery dV/dt <sup>c</sup>	-5.0	V/ns
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$
RthJA	Maximum Junction-to-Ambient	62	$^\circ C/W$
RthCS	Case-to-Sink, Flat, Greased Surface	0.50	$^\circ C/W$
RthJC	Maximum Junction-to-Case (Drain)	1.0	$^\circ C/W$

## 200V P-Channel Enhancement Mode MOSFET

Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit	
V <sub>DS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	-200	-	-	V	
□V <sub>DS</sub> /T <sub>J</sub>	V <sub>DS</sub> Temperature Coefficient	Reference to 25 °C, I <sub>D</sub> = -1 mA	-	-0.2	-	V/°C	
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-2.0	-	-4.0	V	
I <sub>GSS</sub>	Gate-Source Leakage	V <sub>GS</sub> = ± 20 V	-	-	± 100	nA	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -200 V, V <sub>GS</sub> = 0 V	-	-	-100	μA	
I <sub>DSS</sub>		V <sub>DS</sub> = -160 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	-500		
R <sub>DS(on)</sub>	Drain-Source On-State Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -5.5 A <sup>b</sup>	-	0.34	0.42	Ω	
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> = -50 V, I <sub>D</sub> = -6.6 A <sup>b</sup>	4.1	-	-	S	
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = -25 V, f = 1.0 MHz, see fig. 5	-	1200	-	pF	
C <sub>oss</sub>	Output Capacitance		-	370	-		
C <sub>rss</sub>	Reverse Transfer Capacitance		-	81	-		
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> = -10 V	-	-	44	nC	
Q <sub>gs</sub>	Gate-Source Charge				I <sub>D</sub> = -11 A, V <sub>DS</sub> = -160 V, see fig. 6 and 13 <sup>b</sup>		7.1
Q <sub>gd</sub>	Gate-Drain Charge				27		
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -100 V, I <sub>D</sub> = -11 A R <sub>g</sub> = 9.1 Ω, R <sub>D</sub> = 8.6 Ω, see fig. 10 <sup>b</sup>	-	14	-	ns	
t <sub>r</sub>	Rise Time		-	43	-		
t <sub>d(off)</sub>	Turn-Off Delay Time		-	39	-		
t <sub>f</sub>	Fall Time		-	38	-		
R <sub>g</sub>	Gate Input Resistance	f = 1 MHz, open drain	0.3	-	1.7	Ω	
I <sub>S</sub>	Continuous Source-Drain Diode Current	Between lead, 6 mm (0.25") from package and center of die contact	-	-	-11	A	
I <sub>SM</sub>	Pulsed Diode Forward Current <sup>a</sup>				-44		
V <sub>SD</sub>	Body Diode Voltage	T <sub>J</sub> = 25 °C, I <sub>S</sub> = -11 A, V <sub>GS</sub> = 0 V <sup>b</sup>	-	-	-5	V	
t <sub>rr</sub>	Body Diode Reverse Recovery Time	T <sub>J</sub> = 25 °C, I <sub>F</sub> = -11 A, dI/dt = 100 A/μs <sup>b</sup>	-	250	300	ns	
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	2.9	3.6	μC	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).  
 b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.

## Typical Characteristics

## 200V P-Channel Enhancement Mode MOSFET

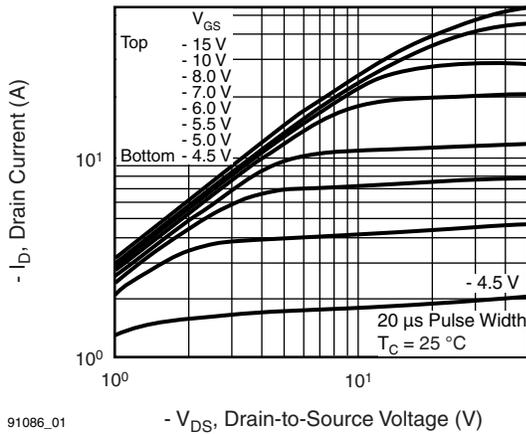


Fig. 1 - Typical Output Characteristics,  $T_C = 25\text{ }^\circ\text{C}$

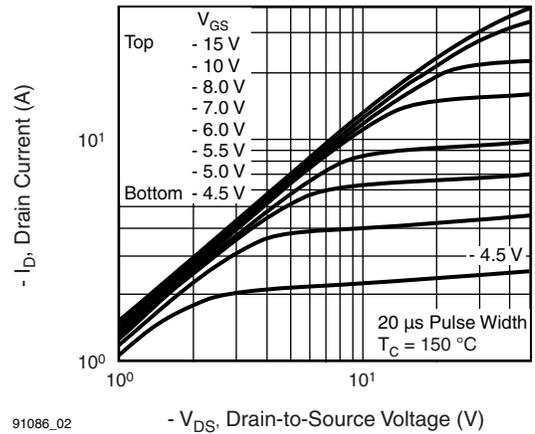


Fig. 2 - Typical Output Characteristics,  $T_C = 150\text{ }^\circ\text{C}$

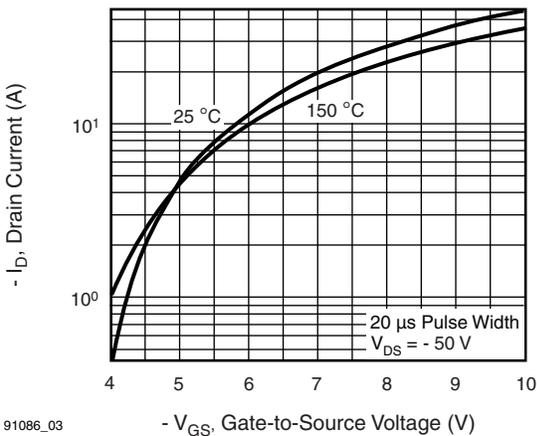


Fig. 3 - Typical Transfer Characteristics

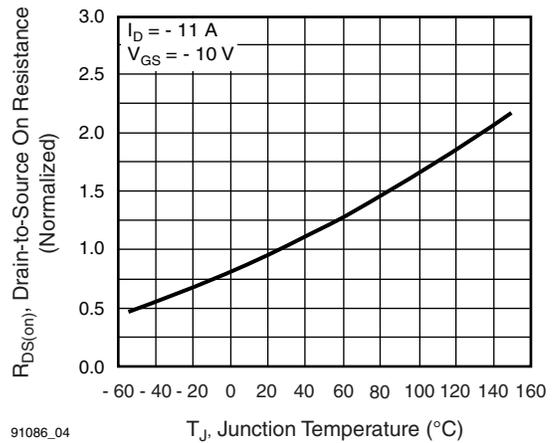


Fig. 4 - Normalized On-Resistance vs. Temperature

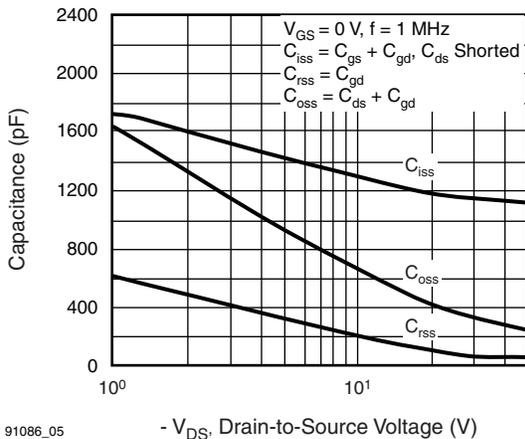


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

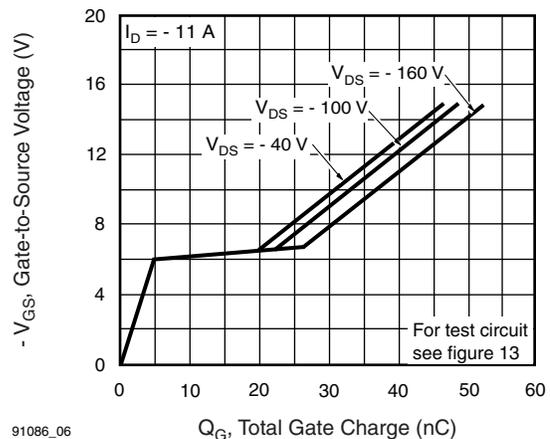


Fig. 6 - Typical Gate Charge vs. Drain-to-Source Voltage

## 200V P-Channel Enhancement Mode MOSFET

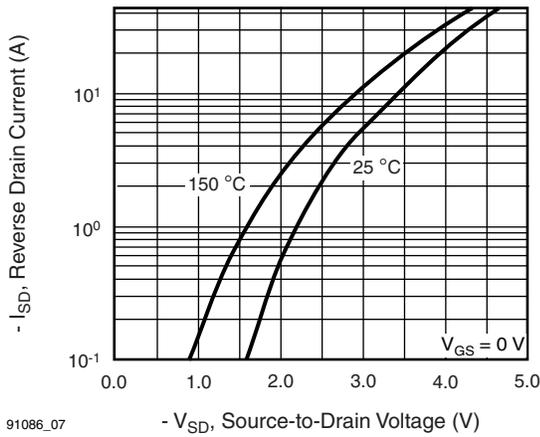


Fig. 7 - Typical Source-Drain Diode Forward Voltage

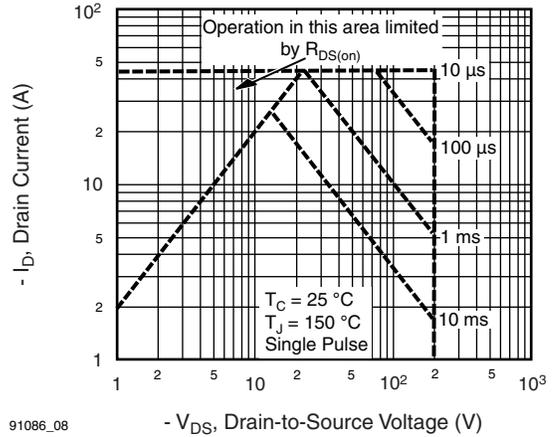


Fig. 8 - Maximum Safe Operating Area

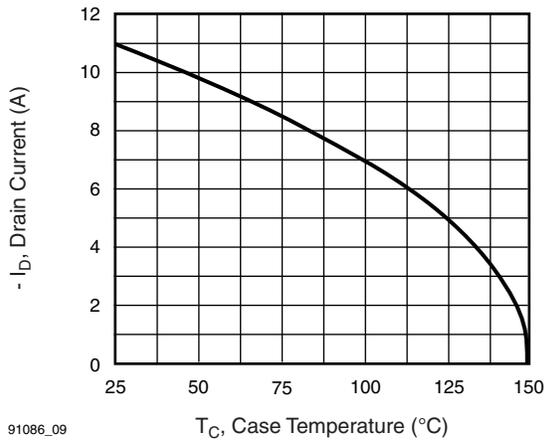


Fig. 9 - Maximum Drain Current vs. Case Temperature

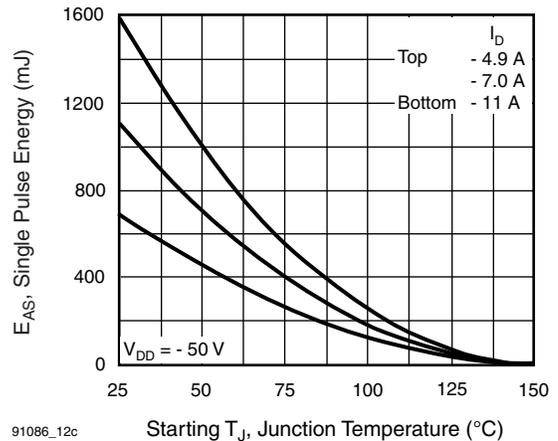


Fig. 10 - Maximum Avalanche Energy vs. Drain Current

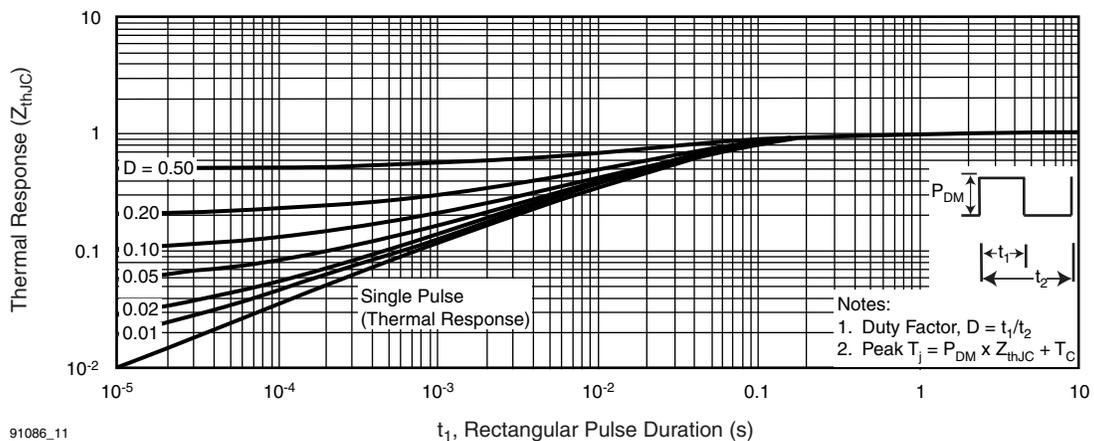


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

## 200V P-Channel Enhancement Mode MOSFET

